

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

APPLICANT : Satoru HANZAWA et al.
SERIAL NO. : (Con. of 10/201,317)
FILING DATE : 25 June 2003
FOR : SEMICONDUCTOR DEVICE
GROUP ART UNIT : 2818 (Anticipated)
EXAMINER : Viet Q. Nguyen (Anticipated)

COMMISSIONER FOR PATENTS
P. O. Box 1450
Alexandria, Virginia 22313-1450

INFORMATION DISCLOSURE STATEMENT
UNDER 37 C.F.R. § 1.97 & § 1.98

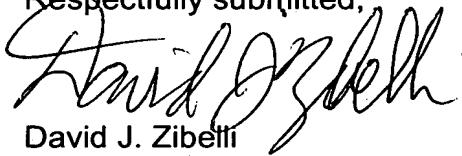
SIR:

In conformance with Applicants' duty of disclosure under 37 C.F.R. § 1.56 and § 1.97(b)(1), the references listed on the attached form PTO-1449 are hereby brought to the Examiner's attention.

Since all the references were already considered in parent application Serial No. 10/201,317, no copies of the references are required.

It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear in the "references cited" on any patent to issue therefrom.

Respectfully submitted,



David J. Zibelli
(Reg. No. 36,394)

Date: 25 June 2003

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FORM PTO-1449**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT(S)**

Atty Docket No. : 29287/137
 Serial No. :
 Inventors : HANZAWA, et al.
 Filed : 25 June 2003
 Group Art Unit : 2818
 Examiner : Viet Q. Nguyen

U.S. PATENT DOCUMENTS

<u>Examiner Initial</u>	<u>Patent Number</u>	<u>Patent Date</u>	<u>Name</u>	<u>Class/ Subclass</u>	<u>Filing Date</u>
_____	6,452,858	09-2002	HANZAWA, et al.	365/230.06	
_____	6,545,897	04-2003	FUJISAWA, et al.	365/230.08	
_____	6,545,525	04-2003	ITOH, et al	327/524	
_____	2001/0028581	10-2001	YANAGISAWA, et al	365/189.05	
_____	2001/0009519	07-2001	FUJISAWA et al.	365/51	
_____	2001/0001598	05-2001	NARUI, et al.	365/149	
_____	6,535,435	03-2003	TANAKA, et al.	365/189.09	
_____	6,501,672	12-2002	SEKIGUCHI, et al.	365/72	
_____	6,480,425	11-2002	YANAGISAWA, et al	365/189.05	
_____	6,452,858	09-2002	HANZAWA, et al.	365/230.06	

FOREIGN PATENT DOCUMENTS

<u>Examiner Initial</u>	<u>Document Number</u>	<u>Date</u>	<u>Country</u>	<u>Class/ Subclass</u>	<u>Translation Yes</u> <u>No</u>

OTHER DOCUMENTS
(Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner Initial

EXAMINER**DATE CONSIDERED**

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE STATEMENT BY APPLICANT PTO FORM 1449	ATTY. DOCKET NO. 29287/137	SERIAL NO. (Con.. of 10/201,317)
	APPLICANT HANZAWA et al.	
	FILING DATE Viet D. Nguyen (Anticipated)	GROUP 2918 (Anticipated)

U. S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE*
	2002/0041531 A1	04/11/02	TANAKA et al.	365	205	

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
	JP 02001195879A	07/01	Japan				
	JP 407057461 A	03/95	Japan				

OTHER DOCUMENTS

EXAMINER INITIAL		AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
		IEEE International Solid-State Circuits Conference, Digest of Technical Papers, 1972, pp. 10-11.*
		IEE Electronics Letters, May 13, 1999, Vol. 35, No. 10, pp. 848-850.*
		European Solid-State Circuits Conference, Digest of Technical Papers, 1992, pp. 131-134.*
		IEEE Journal of Solid-State Circuits, May 2000, Vol. 35, No. 5, pp. 691-695.

*Mentioned in the Specification

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

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